RSFQ devices with selective dissipation for quantum information processing

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We study the possibility to use frequency dependent damping in RSFQ circuits as means to reduce dissipation and consequent decoherence in RSFQ /qubit circuits. We show that stable RSFQ operation can be achieved by shunting the Josephson junctions with an RC circuit instead of a plain resistor. We derive criteria for the stability of such an arrangement, and discuss the e ect on decoherence and the optim isation issues. We also design a simple ux generator aimed at manipulating ux qubits.

Rapid single ux quantum (RSFQ) technology [1] has been suggested as the classical interface for the quantum bits [2], and eventually for a scalable quantum computer. RSFQ technology is inherently dissipative. The dissipation is a likely source of decoherence, which lim its the allowed coupling between the R SFQ circuit and the quantum circuit. It is caused by the dam ping of the Josephson junctions by shunt resistors. The conventional dam ping is, how ever, higher than what is needed for stable operation. Therefore one is encouraged to search solutions to decrease it. One approach is to use nonlinear dam ping in order to switch the damping on only, as a junction is switching [3]. Our approach, on the other hand, is based on the fact that the switching events occur at the tim e scale of the inverse plasm a frequency. Therefore the dam ping at low er frequencies is redundant. The sim plest way to realise the high-pass Itering is to connect a capacitor in series with the shunt resistor. One bene t is that such a circuit is realisable by a conventional Nb/AD x trilayer process [4]. A similar approach has previously been suggested and tested to produce low -noise SQUID m agnetom eters [5, 6], and as m eans to improve the resolution of ux qubit readout circuits [7]. We now show that it is also possible to realise generic full-scale RSFQ circuits with such a con quration. As an example, we introduce a device design able to drive a qubit into a coherent superposition of ux states. The e ect on the decoherence is also discussed.

In simple terms, the stability of an RSFQ circuit is guaranteed by the su cient dam ping of the plasm a resonances of the junctions and of the LC resonances form ed by inductors and junction capacitances. The maximum (zero bias) angular plasm a frequency is $!_p = 1 = \overline{L_J C}$, where $L_J = 0=2$ I_c is the Josephson inductance, C the capacitance and Ic the critical current of junction, and $_0$ = h=2e is the ux quantum . Therefore the Q -value of the plasm a resonance is chosen below unity. For a conventional dam ping scheme (see Fig. 1(a) and (b)), the square of the Q -value is given by the Stewart-M cC um ber parameter $_{c} = 2 I_{c}R_{s}^{2}C = _{0}$, where R_{s} is the shunt resistance and $_0 = h=2e$ is the ux quantum . The inductances of the R SFQ circuit elements are of the same order as the Josephson inductance (or $_{\rm L}$ 2 LL= 0 1), so this simultaneously ensures the dam ping of the LC

resonances.

The junction parameters, inductances, and the shunt resistance can be sim ilarly de ned and their param eters chosen for the RC shunted RSFQ (Fig. 1(c)) as well. The additional component value to be chosen is the shunt capacitance C_s. From the discussion above it follows that a natural additional stability parameter is the ratio of the R_sC_s cuto and the plasm a frequency, namely = $1=!_{p}R_{s}C_{s}$. To test the e ect of on the stability, we simulate the most basic RSFQ element, the Josephson transmission line (JTL). The value of $_{\rm c}$ = 1=2 is xed, while the bias point I_b and the capacitance C_s (or) are varied in order to test the stable range of param eters. W e de ne the system to be stable, if the ux quantum propagates from the left end to the right end correctly as show n in Fig. 2(b). The indications of the lost stability are error pulses (in practice, the ux quantum re ecting back

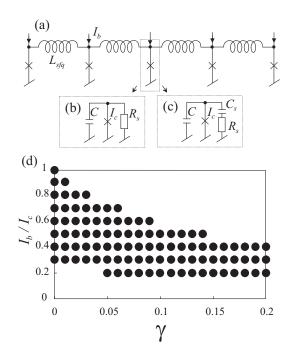


FIG.1: (a) A Josephson transmission line realised with (b) conventional and (c) frequency dependent damping. (d) Stable parameter range as function of $= 1=R_sC_s!_p$ and the bias current I_b scaled to critical current I_c .

from the right end) or junctions switching perm an ently into a nite voltage state. The resulting stable parameter range is shown in Fig. 1 (d). The leftm ost column shows the corresponding result with the conventional JT L (formally with C_s = 1). The decreased stability with RC damping and large bias currents is mainly because the potential barrier protecting against the error pulses is reduced. However, with realistic values of C_s su cient stability can be obtained.

In a practical realisation of the shunt capacitance it is important to avoid parasitic resonances. The wavelength at the plasm a frequency in the capacitor is given as $_{\rm p}$ = 2 c=! $_{\rm p}^{\rm p}$ $\frac{1}{r}$ (1 + 2 $_{\rm L}$ =d), where c is the speed of light, " $_{\rm r}$ is the dielectric constant, $_{\rm L}$ is the London penetration depth of the electrodes, and d is the insulator thickness. To be on the safe side, the dimension of the capacitor should be $_{\rm p}$ =8 at maximum. Therefore for the capacitance (of a square) it applies C $_{\rm s}$. (c)²" $_{\rm 0}$ =16! $_{\rm p}^2$ d (1 + 2 $_{\rm L}$ =d). In other words, realizability dictates that

$$\& \frac{16!_{p}d(1+2_{L}=d)}{{}^{2}R_{s}c^{2}"_{0}} = \frac{32^{p}\overline{2}d(1+2_{L}=d)}{{}_{0}"_{0}c^{2}}I_{c}; \quad (1)$$

where in the last form the de nition of the plasma frequency and $_{\rm c}$ = 1=2 have been used. The minimum realizable depends only on the critical current, capacitor thickness and the London penetration depth. It is also favorable to use a small critical current, which is in accordance to minim ising the heating e ects. For exam – ple, an existing Nb process for milli-K elvin applications has Nb₂O₅ capacitors with d = 140 nm, $_{\rm L}$ = 90 nm, and typically I_c = 3 A, whence it follows & 0:008 thus enabling the operation well in the stable regime (see Fig. 1 (d)).

We test next RC damping by simulating a simple device (Fig. 2 (a)) able to generate rectangular fast rise-tim e ux-pulses. The device consists of two DC/SFQ converters [8] driving an RS ip- op [1]. The generator takes two periodic (e.g. sinusoidal) mutually phase-locked signals as inputs, and produces a ux through the output coil L_{10} . The frequency of the ux pulses is the frequency of the input signals, and the pulse length is related to the phase di erence of them . Resulting simulated time domain plots are shown in Figs. 2 (b) and 2 (c). The pulses with am plitude $_0$ can e.g. be used in manipulating a ux-type qubit [9], provided the coupling between the device and the qubit is strong enough. W ith such a device one avoids the need of wide-band wiring and consequent noise from the room temperature electronics. A further bene t is relative sim plicity.

The e ect of drive and readout circuits on quantum circuits depends largely on the qubit type and the realisation of the classical circuit. Here we consider in general terms qubits, whose ux degree of freedom [10, 11, 12, 13, 14] is inductively coupled to an RSFQ

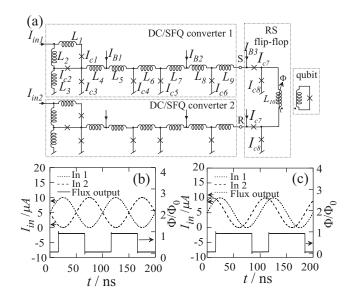


FIG.2: (a) A ux pulse generator circuit coupled to a ux qubit. All the Josephson junctions of the RSFQ circuit are damped with RC shunts, which are not shown for clarity. b) and (c) simulated tim e-dom ain plots of the RSFQ circuit. The parameters used here are $I_{c1} \dots I_{c7} = I_0$, $I_{c8} = 1.4I_0$, $I_{b1} = 1.6I_0$, $I_{b2} = 1.5I_0$, $I_{b3} = 0.7I_0$, where $I_0 = 2.9$ A and $L_1 = 0.35L_0$, $L_2 = 0.33L_0$, $L_3 = L_6 = 0.6L_0$, $L_4 = 0.1L_0$, $L_5 = 0.3L_0$, $L_7 = L_8 = 0.5L_0$, $L_9 = L_0$, and $L_{10} = 2.5L_0$, where $L_0 = 357$ pH. In addition $!_p = 2$ 19 GHz, $_c = 0.51$ and = 0.1.

circuit (Fig. 3(a)). This type of an experiment bene ts probably most from the frequency dependent damping.

The dissipation can be modelled as a frequency dependent e ective resistance in parallel to the qubit inductance coupled to the RSFQ circuit (Fig. 3 (b)). The effective resistance R_{eff} is calculated for both conventional and RC shunted RSFQ in Fig. 3 (c). For the conventional RSFQ R_{eff} is constant at low frequencies leading to constant dissipation

$$R_{eff;0} = b \frac{R_s}{k^2} \frac{L_q}{L_{sfq}}; \qquad (2)$$

where L_q is an inductance of the qubit, L_{sfq} is the inductance of the RSFQ circuit, k is the coupling between the two, and b depends on the details of the RSFQ circuit. Taking only the nearest elements of the RSFQ circuit into account, we get b = $(1=2)(1+4(L_JL_{sfg}+L_{sfg}^2)=L_J^2)$, where the term s of order k^2 have been dropped. For the conventionalRSFQ technology, the dissipation is ohm ic, i.e. the environm ent spectral density J_1 (!) = (=2) ~! [14, 15]. The decoherence time is typically inversely proportional to $J_1(!_q)$, where $!_q = E = w$ ith E the energy level splitting of the qubit [15]. For a ux type qubit the dissipation parameter = B $R_{q}=R_{eff}$;0, where $R_{q} = h = 4e^{2}$ is the quantum resistance and B 1 is a constant dependent on the qubit details [9]. The m in im um requirem ent for coherent operation (the weak-

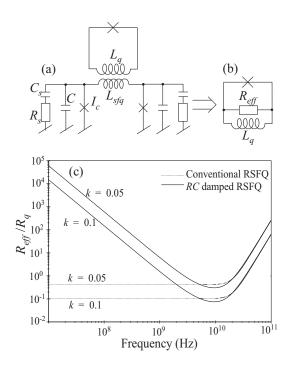


FIG. 3: Calculation of the e ective damping resistance of a ux qubit coupled to an RSFQ circuit. The example parameters used here are $L_{sfq} = 357 \text{ pH}$, $L_q = 10 \text{ pH}$, $I_c = 3 \text{ A}$, $_c = 0.5$, and = 0.2.

dam ping lim it) is that 1. E g. with param eters used in Fig. 3 this leads to the requirem ent of the coupling factor k 0.03. This in turn leads to severe lim itations in the resolution of a readout application, or a lim ited ux am plitude in the generation of drive signals.

In case of RC shunted RSFQ the corresponding gure is

$$R_{eff} (!) = \frac{R_{eff;0}}{(!R_{s}C_{s})^{2}} = R_{eff;0} \frac{!p}{!}^{2} : (3)$$

This leads to superohm ic spectral density J_2 (!) = (=2) ($!_p$)² ~!³ [7, 15], and the improvement in the decoherence time (if limited by the RSFQ circuit) is ($!_p=!_q$)², provided $!_q$!p. This enables signi cant increase in k, even close to unity.

To optim ise an RSFQ/qubit system, R_{eff} should be m axim ised. Since $R_{eff} / {}^2$ (Eq. (3)), should be chosen as large as possible. The drawback is, though, that the stability against the parameter spread is decreased (see Fig. 1(d)). Another possibility is to increase the plasm a frequency, i.e. increase the critical current density J_c . It can be shown that R_{eff} is proportional to $J_c^{3=2}$, if L_q , the stability parameters and k are held constant. Therefore it is favorable to use large J_c , which is also favorable in terms on m axim ising the RSFQ speed. To simultaneously minim ise the self-heating e ects, one should have sm all I_c junctions [16]. Therefore large J_c junctions with sm all areas are optim al. However, if the area is limited by the fabrication, one needs to com prom ise between the speed, the dissipation experienced by the qubit, and the heating e ects.

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